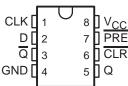
#### SN74LVC2G74 SINGLE POSITIVE-EDGE-TRIGGERED D-TYPE FLIP-FLOP WITH CLEAR AND PRES

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- **Available in the Texas Instruments** NanoStar™ and NanoFree™ Packages
- Supports 5-V V<sub>CC</sub> Operation
- Inputs Accept Voltages to 5.5 V
- Max tpd of 5.9 ns at 3.3 V
- Low Power Consumption, 10-µA Max I<sub>CC</sub>
- ±24-mA Output Drive at 3.3 V
- Typical V<sub>OI P</sub> (Output Ground Bounce) <0.8 V at  $V_{CC} = 3.3 \text{ V}, T_A = 25^{\circ}\text{C}$
- Typical V<sub>OHV</sub> (Output V<sub>OH</sub> Undershoot) >2 V at  $V_{CC}$  = 3.3 V,  $T_A$  = 25°C
- **I**off Supports Partial-Power-Down Mode Operation
- Latch-Up Performance Exceeds 100 mA Per JESD 78, Class II
- **ESD Protection Exceeds JESD 22** 
  - 2000-V Human-Body Model (A114-A)
  - 200-V Machine Model (A115-A)
  - 1000-V Charged-Device Model (C101)

# **DCT OR DCU PACKAGE** (TOP VIEW)



#### YEA, YEP, YZA, OR YZP PACKAGE (BOTTOM VIEW)

		l
04	50	Q
○3	60	CLR
02	70	PRE
01	80	Vcc
	○3 ○2	04 50 03 60 02 70 01 80

#### description/ordering information

This single positive-edge-triggered D-type flip-flop is designed for 1.65-V to 5.5-V V<sub>CC</sub> operation.

NanoStar™ and NanoFree™ package technology is a major breakthrough in IC packaging concepts, using the die as the package.

#### ORDERING INFORMATION

TA	PACKAGE <sup>†</sup>	PACKAGE <sup>†</sup>		
	NanoStar™ WCSP (DSBGA) – YEA		SN74LVC2G74YEAR	
	NanoFree™ WCSP (DSBGA) – YZA (Pb-free)	D I . ( 0000	SN74LVC2G74YZAR	0.0
-40°C to 85°C	NanoStar™ – WCSP (DSBGA) 0.23-mm Large Bump – YEP	Reel of 3000	SN74LVC2G74YEPR	CP_
	NanoFree™ – WCSP (DSBGA) 0.23-mm Large Bump – YZP (Pb-free)		SN74LVC2G74YZPR	
	SSOP - DCT	Reel of 3000	SN74LVC2G74DCTR	C74
	VSSOP – DCU	Reel of 3000	SN74LVC2G74DCUR	C74
	1 4350F - DCU	Reel of 250	SN74LVC2G74DCUT	C74_

<sup>†</sup>Package drawings, standard packing quantities, thermal data, symbolization, and PCB design guidelines are available at www.ti.com/sc/package.

DCT: The actual top-side marking has three additional characters that designate the year, month, and assembly/test site. DCU: The actual top-side marking has one additional character that designates the assembly/test site. YEA/YZA, YEP/YZP: The actual top-side marking has three preceding characters to denote year, month, and sequence code, and one following character to designate the assembly/test site. Pin 1 identifier indicates solder-bump composition  $(1 = SnPb, \bullet = Pb-free).$ 



Please be aware that an important notice concerning availability, standard warranty, and use in critical applications of Texas Instruments semiconductor products and disclaimers thereto appears at the end of this data sheet.

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#### description/ordering information (continued)

A low level at the preset  $(\overline{PRE})$  or clear  $(\overline{CLR})$  input sets or resets the outputs, regardless of the levels of the other inputs. When  $\overline{PRE}$  and  $\overline{CLR}$  are inactive (high), data at the data (D) input meeting the setup time requirements is transferred to the outputs on the positive-going edge of the clock pulse. Clock triggering occurs at a voltage level and is not related directly to the rise time of the clock pulse. Following the hold-time interval, data at the D input can be changed without affecting the levels at the outputs.

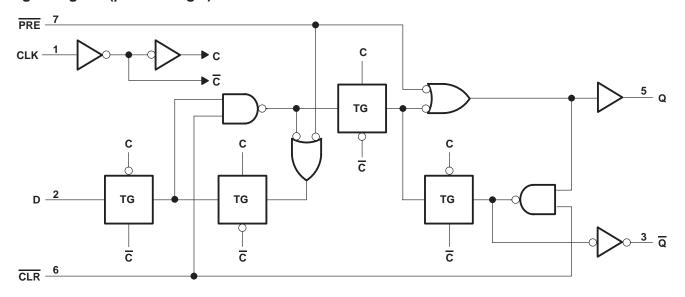
This device is fully specified for partial-power-down applications using  $I_{off}$ . The  $I_{off}$  circuitry disables the outputs, preventing damaging current backflow through the device when it is powered down.

#### **FUNCTION TABLE**

	INP	UTS		OUTI	PUTS
PRE	CLR	CLK	D	Q	Q
L	Н	Х	Χ	Н	L
Н	L	X	Χ	L	Н
L	L	X	Χ	н†	H <sup>†</sup>
Н	Н	$\uparrow$	Н	Н	L
Н	Н	$\uparrow$	L	L	Н
Н	Н	L	Χ	$Q_0$	$\overline{Q}_0$

<sup>†</sup> This configuration is nonstable; that is, it does not persist when  $\overline{\mathsf{PRE}}$  or  $\overline{\mathsf{CLR}}$  returns to its inactive (high) level.

#### logic diagram (positive logic)





#### SN74LVC2G74 SINGLE POSITIVE-EDGE-TRIGGERED D-TYPE FLIP-FLOP WITH CLEAR AND PRESET

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# 

absolute maximum ratings over operating free-air temperature range (unless otherwise noted)†

Voltage range applied to any output in the high-impedance or power-off state, VO	
(see Note 1)	–0.5 V to 6.5 V
Voltage range applied to any output in the high or low state, VO	
(see Notes 1 and 2)	$-0.5 \text{ V to V}_{CC} + 0.5 \text{ V}$
Input clamp current, I <sub>IK</sub> (V <sub>I</sub> < 0)	
Output clamp current, I <sub>OK</sub> (V <sub>O</sub> < 0)	–50 mA
Continuous output current, IO	±50 mA
Continuous current through V <sub>CC</sub> or GND	±100 mA
Package thermal impedance, θ <sub>JA</sub> (see Note 3): DCT package	220°C/W
DCU package	227°C/W
YEA/YZA package	140°C/W
YEP/YZP package	102°C/W
Storage temperature range, T <sub>stq</sub>	

<sup>†</sup> Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTES: 1. The input negative-voltage and output voltage ratings may be exceeded if the input and output current ratings are observed.

- 2. The value of V<sub>CC</sub> is provided in the recommended operating conditions table.
- 3. The package thermal impedance is calculated in accordance with JESD 51-7.



### SN74LVC2G74 SINGLE POSITIVE-EDGE-TRIGGERED D-TYPE FLIP-FLOP WITH CLEAR AND PRESET

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#### recommended operating conditions (see Note 4)

			MIN	MAX	UNIT
	Our arbour Mana	Operating	1.65	5.5	.,
VCC	Supply voltage	Data retention only	1.5		V
		V <sub>CC</sub> = 1.65 V to 1.95 V	0.65 × V <sub>CC</sub>		
.,	LPak Java Carata attana	V <sub>CC</sub> = 2.3 V to 2.7 V	1.7		.,
$V_{\text{IH}}$	High-level input voltage	V <sub>CC</sub> = 3 V to 3.6 V	2		V
		$V_{CC} = 4.5 \text{ V to } 5.5 \text{ V}$	$0.7 \times V_{CC}$		
		V <sub>CC</sub> = 1.65 V to 1.95 V		$0.35 \times V_{CC}$	
.,	Law Israel Sanut wells as	V <sub>CC</sub> = 2.3 V to 2.7 V		0.7	.,
$V_{IL}$	Low-level input voltage	V <sub>CC</sub> = 3 V to 3.6 V		0.8	V
		V <sub>CC</sub> = 4.5 V to 5.5 V		0.3 × V <sub>CC</sub>	
٧ <sub>I</sub>	Input voltage		0	5.5	V
٧o	Output voltage		0	VCC	V
		V <sub>CC</sub> = 1.65 V		-4	
		V <sub>CC</sub> = 2.3 V		-8	
loh	High-level output current			-16	mA
		VCC = 3 V		-24	
		V <sub>CC</sub> = 4.5 V		-32	
		V <sub>CC</sub> = 1.65 V		4	
		V <sub>CC</sub> = 2.3 V		8	
loL	Low-level output current			16	mA
-		VCC = 3 V		24	
		V <sub>CC</sub> = 4.5 V		32	
		V <sub>CC</sub> = 1.8 V ± 0.15 V, 2.5 V ± 0.2 V		20	
Δt/Δν	Input transition rise or fall rate	$V_{CC} = 3.3 \text{ V} \pm 0.3 \text{ V}$		10	ns/V
		V <sub>CC</sub> = 5 V ± 0.5 V		5	
T <sub>A</sub>	Operating free-air temperature		-40	85	°C

NOTE 4: All unused inputs of the device must be held at V<sub>CC</sub> or GND to ensure proper device operation. Refer to the TI application report, *Implications of Slow or Floating CMOS Inputs*, literature number SCBA004.



#### SN74LVC2G74 SINGLE POSITIVE-EDGE-TRIGGERED D-TYPE FLIP-FLOP WITH CLEAR AND PRESET

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# electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PA	RAMETER	TEST CONDITIONS	V <sub>CC</sub>	MIN	TYP	MAX	UNIT
		$I_{OH} = -100  \mu A$	1.65 V to 5.5 V	V <sub>CC</sub> -0.1			
		$I_{OH} = -4 \text{ mA}$	1.65 V	1.2			
l		$I_{OH} = -8 \text{ mA}$	2.3 V	1.9			
Vон		$I_{OH} = -16 \text{ mA}$		2.4			V
		I <sub>OH</sub> = -24 mA	3 V	2.3			
		I <sub>OH</sub> = -32 mA	4.5 V	3.8			
		I <sub>OL</sub> = 100 μA	1.65 V to 5.5 V			0.1	
		I <sub>OL</sub> = 4 mA	1.65 V			0.45	
		I <sub>OL</sub> = 8 mA	2.3 V			0.3	
VOL		I <sub>OL</sub> = 16 mA	0.1/			0.4	V
		$I_{OL} = 24 \text{ mA}$	3 V			0.55	
		I <sub>OL</sub> = 32 mA	4.5 V			0.55	
II	Data or Control inputs	V <sub>I</sub> = 5.5 V or GND	0 to 5.5 V			±5	μΑ
l <sub>off</sub>		$V_I$ or $V_O = 5.5 V$	0			±10	μΑ
ICC		$V_I = 5.5 \text{ V or GND}, \qquad I_O = 0$	1.65 V to 5.5 V			10	μΑ
∆lCC		One input at V <sub>CC</sub> – 0.6 V, Other inputs at V <sub>CC</sub> or GND	3 V to 5.5 V			500	μΑ
Ci		$V_I = V_{CC}$ or GND	3.3 V		5		pF

 $<sup>\</sup>overline{\dagger}$  All typical values are at V<sub>CC</sub> = 3.3 V, T<sub>A</sub> = 25°C.

# timing requirements over recommended operating free-air temperature range (unless otherwise noted) (see Figure 1)

			V <sub>CC</sub> = ± 0.1		V <sub>CC</sub> =		V <sub>CC</sub> =		± 0.9		UNIT
			MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	
fclock	<			80		175		175		200	MHz
	Dulas duration	CLK	6.2		2.7		2.7		2		
t <sub>W</sub>	Pulse duration	PRE or CLR low	6.2		2.7		2.7		2		ns
	0 - turn than a land and 01.16*	Data	2.9		1.7		1.3		1.1		
t <sub>su</sub>	Setup time, before CLK↑	PRE or CLR inactive	1.9		1.4		1.2		1		ns
th	Hold time, data after CLK↑		0		0.3		1.2		0.5		ns

# switching characteristics over recommended operating free-air temperature range (unless otherwise noted) (see Figure 1)

PARAMETER	FROM	TO	V <sub>CC</sub> =		V <sub>CC</sub> =		V <sub>CC</sub> =		У <b>СС</b> =		UNIT
	(INPUT)	(OUTPUT)	MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	
f <sub>max</sub>			80		175		175		200		MHz
	0114	Q	4.8	13.4	2.2	7.1	2.2	5.9	1.4	4.1	
t <sub>pd</sub>	CLK	Ια	6	14.4	3	7.7	2.6	6.2	1.6	4.4	ns
	PRE or CLR	Q or Q	4.4	12.9	2.3	7	1.7	5.9	1.6	4.1	



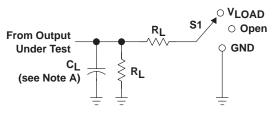
# SN74LVC2G74 SINGLE POSITIVE-EDGE-TRIGGERED D-TYPE FLIP-FLOP WITH CLEAR AND PRESET SCES203K - APRIL 1999 - REVISED SEPTEMBER 2003

# operating characteristics, $T_A = 25^{\circ}C$

PARAMETER		TEST CONDITIONS	V <sub>CC</sub> = 1.8 V	V <sub>CC</sub> = 2.5 V	V <sub>CC</sub> = 3.3 V	V <sub>CC</sub> = 5 V	LINUT
		TEST CONDITIONS TYP		TYP TYP		TYP	UNIT
C <sub>pd</sub>	Power dissipation capacitance	f = 10 MHz	35	35	37	40	pF

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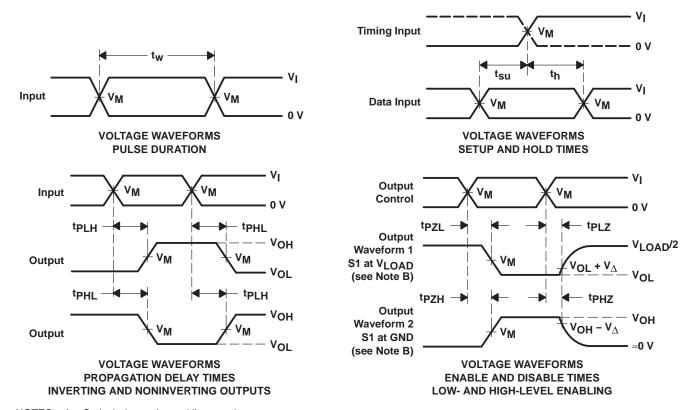
#### PARAMETER MEASUREMENT INFORMATION



TEST	S1
tPLH/tPHL	Open
tPLZ/tPZL	VLOAD
<sup>t</sup> PHZ <sup>/t</sup> PZH	GND

LOAD CIRCUIT

W	INF	PUTS		V	0	6	, ,
VCC	٧ <sub>I</sub>	t <sub>r</sub> /t <sub>f</sub>	VM	VLOAD	CL	$R_L$	$oldsymbol{V}_\Delta$
1.8 V $\pm$ 0.15 V	VCC	≤ <b>2</b> ns	V <sub>CC</sub> /2	2×V <sub>CC</sub>	30 pF	<b>1 k</b> Ω	0.15 V
2.5 V $\pm$ 0.2 V	VCC	≤ <b>2</b> ns	V <sub>CC</sub> /2	2×VCC	30 pF	500 $\Omega$	0.15 V
3.3 V $\pm$ 0.3 V	3 V	≤2.5 ns	1.5 V	6 V	50 pF	500 $\Omega$	0.3 V
5 V $\pm$ 0.5 V	VCC	≤2.5 ns	V <sub>CC</sub> /2	2×V <sub>CC</sub>	50 pF	500 $\Omega$	0.3 V



NOTES: A. C<sub>I</sub> includes probe and jig capacitance.

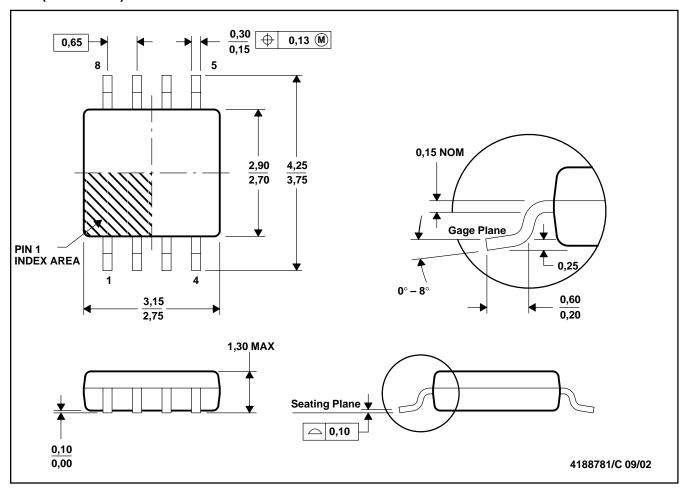
- B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
- C. All input pulses are supplied by generators having the following characteristics: PRR ≤ 10 MHz, Z<sub>Ω</sub> = 50 Ω.
- D. The outputs are measured one at a time with one transition per measurement.
- E. tpLZ and tpHZ are the same as tdis.
- F. tpzL and tpzH are the same as ten.
- G. tpLH and tpHL are the same as tpd.
- H. All parameters and waveforms are not applicable to all devices.

Figure 1. Load Circuit and Voltage Waveforms



#### DCT (R-PDSO-G8)

#### PLASTIC SMALL-OUTLINE PACKAGE

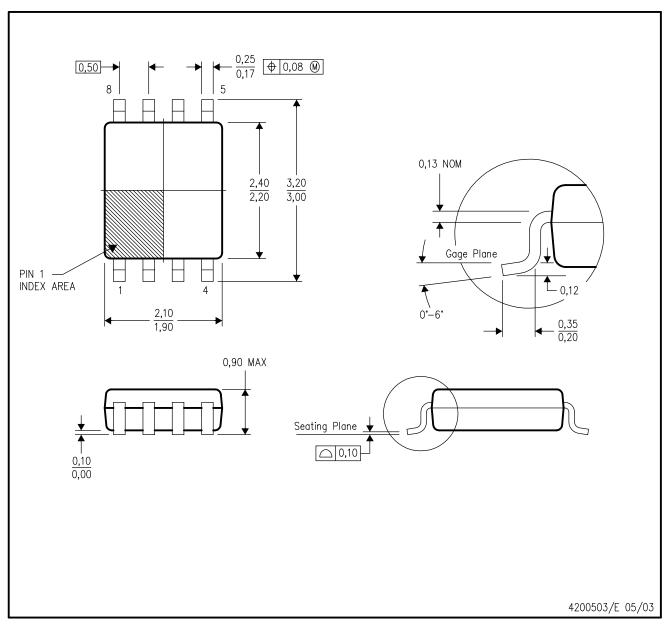


NOTES: A. All linear dimensions are in millimeters.

- B. This drawing is subject to change without notice.
- C. Body dimensions do not include mold flash or protrusion
- D. Falls within JEDEC MO-187 variation DA.

# DCU (R-PDSO-G8)

# PLASTIC SMALL-OUTLINE PACKAGE (DIE DOWN)



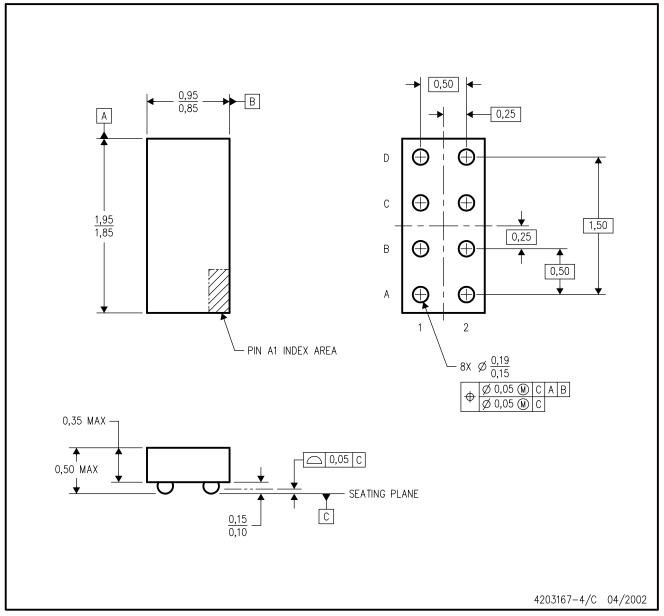
NOTES:

- A. All linear dimensions are in millimeters.
- B. This drawing is subject to change without notice.
- C. Body dimensions do not include mold flash or protrusion.
- D. Falls within JEDEC MO-187 variation CA.



# YEA (R-XBGA-N8)

# DIE-SIZE BALL GRID ARRAY



NOTES: A. All linear dimensions are in millimeters.

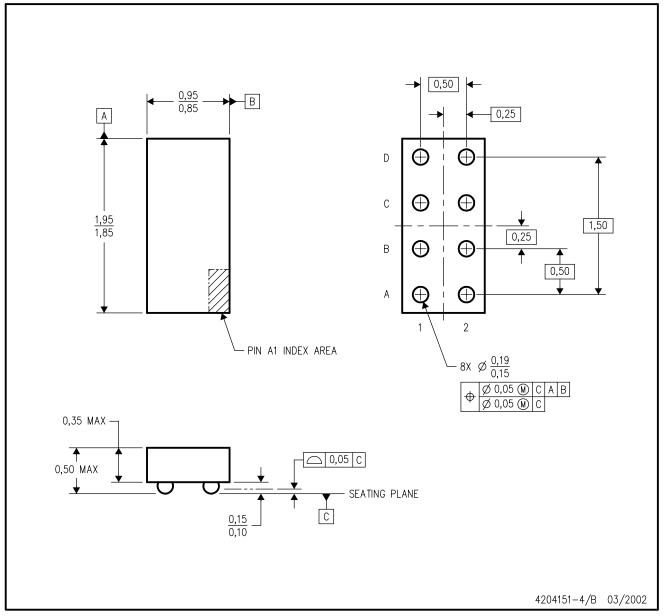
- B. This drawing is subject to change without notice.
- C. NanoStar  $\mathbf{M}$  package configuration.
- D. Package complies to JEDEC MO-211 variation EB.
- E. This package is tin-lead (SnPb). Refer to the 8 YZA package (drawing 4204151) for lead-free.

NanoStar is a trademark of Texas Instruments.



# YZA (R-XBGA-N8)

# DIE-SIZE BALL GRID ARRAY



NOTES: A. All linear dimensions are in millimeters.

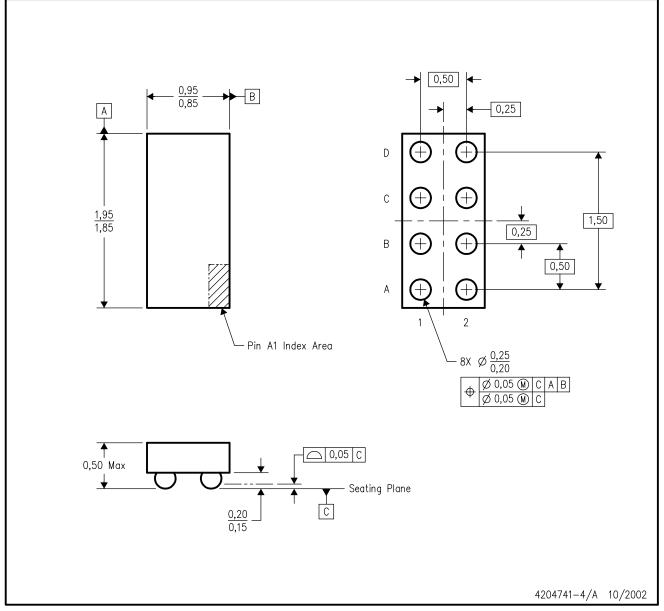
- B. This drawing is subject to change without notice.
- C. NanoFree™ package configuration.
- D. Package complies to JEDEC MO-211 variation EB.
- E. This package is lead-free. Refer to the 8 YEA package (drawing 4203167) for tin-lead (SnPb).

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# YZP (R-XBGA-N8)

# DIE-SIZE BALL GRID ARRAY



NOTES: A. All linear dimensions are in millimeters.

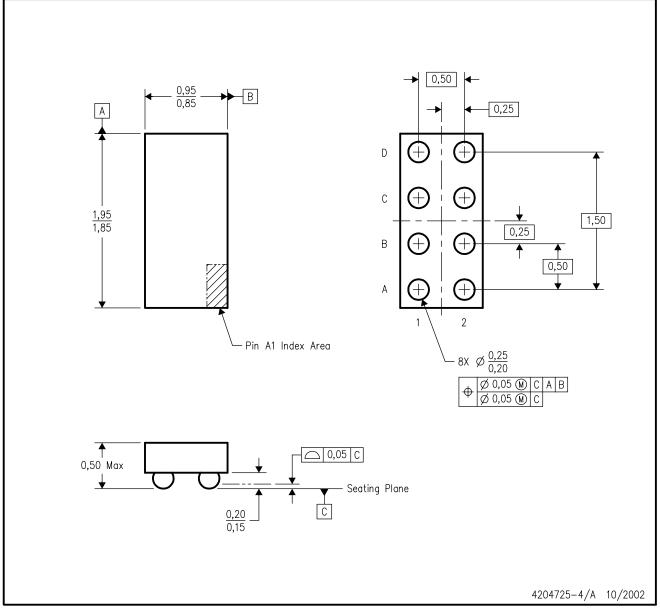
- B. This drawing is subject to change without notice.
- C. NanoFree  $^{\text{TM}}$  package configuration.
- D. This package is lead-free. Refer to the 8 YEP package (drawing 4204725) for tin-lead (SnPb).

NanoFree is a trademark of Texas Instruments.



# YEP (R-XBGA-N8)

# DIE-SIZE BALL GRID ARRAY



NOTES: A. All linear dimensions are in millimeters.

- B. This drawing is subject to change without notice.
- C. NanoStar  $\mathbf{M}$  package configuration.
- D. This package is tin-lead (SnPb). Refer to the 8 YZP package (drawing 4204741) for lead-free.

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